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Sommario/riassunto

This book enlightens readers on the basic surface properties and distance-dependent intersurface forces one must understand to obtain even simple data from an atomic force microscope (AFM). The material becomes progressively more complex throughout the book, explaining details of calibration, physical origin of artifacts, and signal/noise limitations. Coverage spans imaging, materials property characterization, in-liquid interfacial analysis, tribology, and electromagnetic interactions. "Supplementary material for this book can be found by entering ISBN 9780470638828 on booksuppo